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NOTICE OF ALLOWANCE AND FEE(S) DUE

25944

7590

03/16/2010

OLIFF & BERRIDGE, PLC P.O. BOX 320850 ALEXANDRIA, VA 22320-4850 EXAMINER
RIDDLE, CHRISTINA A
ART UNIT PAPER NUMBER

2882 DATE MAILED: 03/16/2010

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/594,836	07/18/2007	Shinichi Okita	129559	3656

TITLE OF INVENTION: ALIGNMENT CONDITION DETERMINATION METHOD AND APPARATUS OF THE SAME, AND EXPOSURE METHOD AND APPARATUS OF THE SAME

APPLN. TYPE	SMALL ENTITY	ISSUE FEE DUE	PUBLICATION FEE DUE	PREV. PAID ISSUE FEE	TOTAL FEE(S) DUE	DATE DUE
nonprovisional	NO	\$1510	\$300	\$0	\$1810	06/16/2010

THE APPLICATION IDENTIFIED ABOVE HAS BEEN EXAMINED AND IS ALLOWED FOR ISSUANCE AS A PATENT. PROSECUTION ON THE MERITS IS CLOSED. THIS NOTICE OF ALLOWANCE IS NOT A GRANT OF PATENT RIGHTS. THIS APPLICATION IS SUBJECT TO WITHDRAWAL FROM ISSUE AT THE INITIATIVE OF THE OFFICE OR UPON PETITION BY THE APPLICANT. SEE 37 CFR 1.313 AND MPEP 1308.

THE ISSUE FEE AND PUBLICATION FEE (IF REQUIRED) MUST BE PAID WITHIN THREE MONTHS FROM THE MAILING DATE OF THIS NOTICE OR THIS APPLICATION SHALL BE REGARDED AS ABANDONED. THIS STATUTORY PERIOD CANNOT BE EXTENDED. SEE 35 U.S.C. 151. THE ISSUE FEE DUE INDICATED ABOVE DOES NOT REFLECT A CREDIT FOR ANY PREVIOUSLY PAID ISSUE FEE IN THIS APPLICATION. IF AN ISSUE FEE HAS PREVIOUSLY BEEN PAID IN THIS APPLICATION (AS SHOWN ABOVE), THE RETURN OF PART B OF THIS FORM WILL BE CONSIDERED A REQUEST TO REAPPLY THE PREVIOUSLY PAID ISSUE FEE TOWARD THE ISSUE FEE NOW DUE.

HOW TO REPLY TO THIS NOTICE:

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If the SMALL ENTITY is shown as YES, verify your current SMALL ENTITY status:

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III. All communications regarding this application must give the application number. Please direct all communications prior to issuance to Mail Stop ISSUE FEE unless advised to the contrary.

IMPORTANT REMINDER: Utility patents issuing on applications filed on or after Dec. 12, 1980 may require payment of maintenance fees. It is patentee's responsibility to ensure timely payment of maintenance fees when due.

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Complete and send this form, together with applicable fee(s), to: Mail Mail Stop ISSUE FEE

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							(Date)
APPLICATION NO.	FILING DATE		FIRST NAMED INVENTOR	₹	ATTC	RNEY DOCKET NO.	CONFIRMATION NO.
10/594,836	07/18/2007	•	Shinichi Okita			129559	3656
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APPLN. TYPE	SMALL ENTITY	ISSUE FEE DUE	PUBLICATION FEE DUE	PREV. PAID ISSU	E FEE	TOTAL FEE(S) DUE	DATE DUE
nonprovisional	NO	\$1510	\$300	\$0		\$1810	06/16/2010
EXAM	INER	ART UNIT	CLASS-SUBCLASS]			
RIDDLE, CH	IRISTINA A	2882	355-053000	-			
 Change of correspondence address or indication of "Fee Address" (37 CFR 1.363). Change of correspondence address (or Change of Correspondence Address form PTO/SB/122) attached. "Fee Address" indication (or "Fee Address" Indication form PTO/SB/47; Rev 03-02 or more recent) attached. Use of a Custome Number is required. 			(1) the names of up to agents OR, alternat (2) the name of a sing registered attorney or	f a single firm (having as a member a rney or agent) and the names of up to tent attorneys or agents. If no name is			
PLEASE NOTE: Unl recordation as set forth (A) NAME OF ASSIC	ess an assignee is ident h in 37 CFR 3.11. Comp GNEE	ified below, no assignee oletion of this form is NC	T a substitute for filing an (B) RESIDENCE: (CIT)	patent. If an assign assignment. Y and STATE OR C	COUNT	TRY)	ocument has been filed for
Please check the appropri	iate assignee category or	categories (will not be p	rinted on the patent):	Individual 🖵 Co	orporat	ion or other private gro	oup entity Government
	are submitted: fo small entity discount p # of Copies	permitted)	b. Payment of Fee(s): (Ple	rd. Form PTO-2038	is atta	ached.	
	s SMALL ENTITY statu	ıs. See 37 CFR 1.27.	b. Applicant is no lo				
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10/594,836	07/18/2007	Shinichi Okita	129559	3656	
25944 75	25944 7590 03/16/2010			INER	
OLIFF & BERRIDGE, PLC			RIDDLE, CHRISTINA A		
P.O. BOX 320850 ALEXANDRIA, VA 22320-4850			ART UNIT	PAPER NUMBER	
			2882		
			DATE MAILED: 03/16/201	0	

Determination of Patent Term Adjustment under 35 U.S.C. 154 (b)

(application filed on or after May 29, 2000)

The Patent Term Adjustment to date is 341 day(s). If the issue fee is paid on the date that is three months after the mailing date of this notice and the patent issues on the Tuesday before the date that is 28 weeks (six and a half months) after the mailing date of this notice, the Patent Term Adjustment will be 341 day(s).

If a Continued Prosecution Application (CPA) was filed in the above-identified application, the filing date that determines Patent Term Adjustment is the filing date of the most recent CPA.

Applicant will be able to obtain more detailed information by accessing the Patent Application Information Retrieval (PAIR) WEB site (http://pair.uspto.gov).

Any questions regarding the Patent Term Extension or Adjustment determination should be directed to the Office of Patent Legal Administration at (571)-272-7702. Questions relating to issue and publication fee payments should be directed to the Customer Service Center of the Office of Patent Publication at 1-(888)-786-0101 or (571)-272-4200.

	Application No.	Applicant(s)	
	10/50/1 926	OKITA, SHINICHI	
Notice of Allowability	10/594,836 Examiner	Art Unit	
	Obstation Bistalia	0000	
	Christina Riddle	2882	
The MAILING DATE of this communication app All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85 NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT R of the Office or upon petition by the applicant. See 37 CFR 1.313	G (OR REMAINS) CLOSED) or other appropriate com- RIGHTS. This application is	in this application. If not included nunication will be mailed in due course.	
1. \boxtimes This communication is responsive to <u>amendments filed 12</u>	2/11/2009 and 12/28/2009.		
2. The allowed claim(s) is/are <u>1-7 and 10-16</u> .			
 3. Acknowledgment is made of a claim for foreign priority u a) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority do 	e been received. e been received in Applica	tion No	m the
International Bureau (PCT Rule 17.2(a)).	ocuments have been recen	ed in this national stage application not	iii tile
* Certified copies not received:			
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.	MENT of this application.		
4. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which giv			OF
5. \square CORRECTED DRAWINGS (as "replacement sheets") mu	st be submitted.		
(a) ☐ including changes required by the Notice of Draftsper		ew (PTO-948) attached	
1) ☐ hereto or 2) ☐ to Paper No./Mail Date	=		
(b) ☐ including changes required by the attached Examiner Paper No./Mail Date	's Amendment / Comment	or in the Office action of	
Identifying indicia such as the application number (see 37 CFR each sheet. Replacement sheet(s) should be labeled as such in			of
6. DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT			e
Attachment(s) 1. ☑ Notice of References Cited (PTO-892)	5. ☐ Notice of	Informal Patent Application	
2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)		Summary (PTO-413),	
3. ☐ Information Disclosure Statements (PTO/SB/08),	Paper N	o./Mail Date ´ 's Amendment/Comment	
Paper No./Mail Date4.		's Statement of Reasons for Allowance	
of Biological Material	9.		
/Peter B. Kim/			
Primary Examiner, Art Unit 2882			

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DETAILED ACTION

Status

1. Acknowledgment is made of the amendment filed on 12/11/2009 which amended claims 1, 2, 10-12, 14, and 16, and cancelled claims 8 and 9. Acknowledgment is made of the supplemental amendment filed 12/28/2009, which amended claims 1, 10, and 11. Claims 1-7 and 10-16 are currently pending. This action is responsive to both the amendment filed on 12/11/2009 and the supplemental amendment filed on 12/28/2009.

Priority

2. Acknowledgment is made of applicant's claim for foreign priority based on an application filed in Japan on 3/31/2004. It is noted, however, that applicant has not filed a certified copy of the JP 2004-105941 application as required by 35 U.S.C. 119(b).

Allowable Subject Matter

- 3. Claim 1-7, 10-16 are allowed.
- 4. The following is an examiner's statement of reasons for allowance.

Regarding claims 1 and 10, the prior art of record, either alone or in combination, fails to teach or render obvious a method for determining alignment parameters that comprises the steps of performing position measurement for sample points in each processing area under predetermined alignment parameters to obtain

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Art Unit: 2882

reference computation results, positioning and processing each processing area at the predetermined processing position based on the references results and measuring a first error to obtain reference processing results, changing part of the predetermined alignment parameters and measuring position of the sample points to obtain comparative computation results by using signal waveforms to change the predetermined alignment parameters to obtain multiple comparative computation results and comparing the multiple comparative computation results with the original reference computation results to select candidates of the comparative computation results based only on the comparison of the original reference results and the comparative computation results. The selected comparative computation results are then used to calculate a second processing error along with the reference computation results and the reference processing results. This limitation in combination with the other limitations of claims 1 and 20 renders the claims non-obvious over the prior art of record.

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Ina et al. (US PGPub 2003/0071980, Ina hereinafter) was relied upon in the non-final rejection filed 9/11/2009. However, the limitation included in the supplemental amendment filed 12/28/2009 that recites comparing alignment measurement results with results obtained by changing alignment parameters and using only this comparison to select the alignment results obtained with changed alignment parameters to be used to calculate a processing error overcomes Ina since Ina discloses also using inspection results to determine parameter values for optimum alignment (Fig. 2, step S255 and S260). Therefore, Ina does not teach using only the measurement results and estimated measurement results as currently required by the claim limitation.

processing conditions.

Irie et al. (US Patent No. 5,525,808, Irie hereinafter) discloses measuring wafer alignment and determining whether the signal processing conditions for detected waveforms are optimal (Fig. 15B, step 114 and Fig. 30A, step 610). However, Irie does describe selecting a condition based only on comparing the results of different signal

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Matsumoto et al. (US PGPub 2003/0202182, Matsumoto hereinafter) discloses performing alignment measurement (AGA measurement in process 11, Fig. 2) and performing alignment measurement with different variables than the processing variable (process 12, Fig. 2). Inspection is performed by an overlay apparatus and the results of inspection and the AGA measurement are used to create a database (Fig. 2, process 15). However, Matsumoto does not describe comparing the results of the different AGA measurements and selecting AGA measurement with other job variables based only on the comparison of AGA measurements.

Oishi et al. (US PGPub 2003/0204282, Oishi hereinafter) discloses performing alignment measurement (AGA measurement in steps S102, Fig. 2B), changing alignment parameters and using the alignment signals to re-perform alignment measurement (Fig. 2B, step S103), and exposing the substrate and measuring resulting overlay (Fig. 2B, steps S104 and S106). The alignment measurement results and overlay measurement results are sent to a PC (Fig. 2B, step S107, step S201, and step S203) and an optimal parameter value is determined by predicting the inspection result for each parameter value (Fig. 2b, step S205). However, Oishi does not appear to describe determining processing errors based on the different AGA measurements and

the inspection results and does not describe selecting job variables based only on the comparison of AGA measurements.

Nakajima (US PGPub 2004/0223157) discloses determining a mark position with different signal processing conditions (Fig. 18, step S22) and determining the differences between the different positions (Fig. 18, step S23). Based on only the comparison between different detection processing conditions, a processing condition is selected and used to perform mark alignment (Fig. 18, step S26). However, Nakajima does not appear to disclose performing position measurement for sample points in each shot on a wafer and performing inspection after exposure processing of the wafer.

Regarding claim 11, the prior art of record, either alone or in combination, fails to teach or render obvious an apparatus for determining alignment parameters comprising a reference computation result fetching means for performing position measurement for sample points in each processing area under predetermined alignment parameters to obtain reference computation results, a reference processing result fetching means for measuring a first error to obtain reference processing results after positioning and processing each processing area at the predetermined processing position based on the references results, and a comparative computation result fetching means for changing part of the predetermined alignment parameters and measuring position of the sample points to obtain comparative computation results by using signal waveforms to change the predetermined alignment parameters to obtain multiple comparative computation results and comparing the multiple comparative computation results with the original reference computation results to select candidates of the

comparative computation results based on the residual error of the comparison of only original reference results and the comparative computation results. The selected comparative computation results are then used by a processing error calculating means for calculating to calculate a second processing error along with the reference computation results and the reference processing results. This limitation in combination with the other limitations of claim 11 renders the claim non-obvious over the prior art of record.

The dependent claims are likewise allowable by virtue of their dependency upon allowable independent claims as stated above.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

5. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

Kobayashi et al. (US Patent No. 6,416,912) discloses changing signal waveform processing conditions to measure alignment marks.

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Any inquiry concerning this communication or earlier communications from the examiner should be directed to Christina Riddle whose telephone number is (571)270-7538. The examiner can normally be reached on Monday- Thursday 7:00-17:30 EST.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Edward Glick can be reached on (571)272-2490. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/Peter B. Kim/ Primary Examiner, Art Unit 2882

/C. R./ Examiner, Art Unit 2882